NOTES:

- 1. SUBSTRATE: Fused Silica
- 2. SURFACE \$1 TO BE PARALLEL TO SURFACE \$2 TO WITHIN <3 ARCMINS
- 3. COATING (APPLY ACROSS COATING APERTURE)

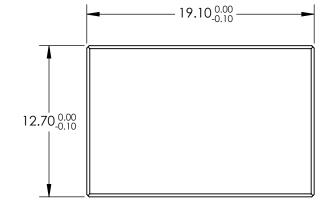
S1: R(ABS) >99.8% @ 1064nm R(ABS) >99.5% @ 1046 - 1074nm DAMAGE THRESHOLD, PULSED: 20 J/cm² @ 1064nm, 20ns, 20Hz CW: 1 MW/cm² @ 1064nm

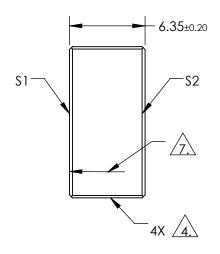
S2: NONE

4. FINE GROUND SURFACE

- 5. CLEAR APERTURE AND COATING APERTURE ARE CENTERED ON SURFACE
- 6. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE

ARROW ON EDGE WITH LASER ETCH, PENCIL, OR PERMANENT INK POINTS TOWARDS SURFACE \$1





FOR INFORMATION ONLY: DO NOT MANUFACTURE PARTS TO THIS DRAWING

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE DIMENSIONS ARE FOR REFERENCE ONLY

	\$1	\$2					
SHAPE	PLANO	PLANO				Edmund Optics	C ®
SURFACE QUALITY	10-5	COMMERCIAL POLISH					5
SURFACE FLATNESS	0.10 WAVE	N/A		1		12.7 x 19.1mm 1064nm 45°, Nd:YAG Laser	rline
MIN CLEAR APERTURE	10.80 x 16.24	N/A	THIRD ANGLE PROJECTION		TITLE	Mirror	1 LII IC
MIN COATNG APERTURE	10.80 x 16.24	N/A					SHEET
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED	ALL DIMS IN	mm	DWG NO	39654	1 OF 1